

Test Your Dream !

AF8651A5/AF8651A7/AF8655C7

Burn-In & Test System

AF8651A5/AF8651A7/AF8655C7 QA applications are designed for specialized engineer application, which can execute simultaneous testing for various kinds of memory device. Our testing system can stimulate various test environments of temperature, DRAM and FLASH devices for many long hours , to ensure the quality and functions of memory products.

- Temperature :
 - AF8651A5 : 70℃ ~ 150℃
 - AF8651A7 : 70℃ ~ 150℃
 - AF8655C7 : -40℃ ~ 150℃
- Item of signals :
 - Add. DRV : 32ch
 - I/O : 72ch
 - CLK DRV : 10 phases
- Power Supply
 - Voltage Range : PS1 / PS2 : 1V~7V / 19A
 - Bump Function : Yes
- Number of Zone : 1 zone (Temp. / Control)
 - 12BIB, 1 rack, 12 BIB / rack
 - 40mm pitch
- PM Check Function : Yes
- Flash Function :
 - AF8651A5 : No
 - AF8651A7 & AF8655C7 : Yes



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